Materials Horizons



CORRECTION

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Correction: Focused ion beam milling of self-assembled magnetic superstructures: an approach to fabricate nanoporous materials with tunable porosity

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Correction for 'Focused ion beam milling of self-assembled magnetic superstructures: an approach to fabricate nanoporous materials with tunable porosity' by Verner Håkonsen et al., Mater. Horiz., 2018, 5, 1211-1218

The axis labels of Fig. 3f and 4f were not displayed in the originally published version of the manuscript. The correct versions of Fig. 3 and 4 are shown below.

The authors would also like to correct a mistake in the Introduction. On page 1211, in the first paragraph of the Introduction the sentence "Here, we fabricate self-assembled superstructures in different morphologies from magnetic nanoparticles of different shapes, and investigate their interaction with a Ga+-ion beam by means of the focus ion beam (FIB) milling technique." should read "Here, we fabricate self-assembled superstructures in different morphologies from magnetic nanoparticles of different shapes, and investigate their interaction with a Ga⁺-ion beam by means of the focused ion beam (FIB) milling technique."

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Ion beam voltage (kV)

Correction

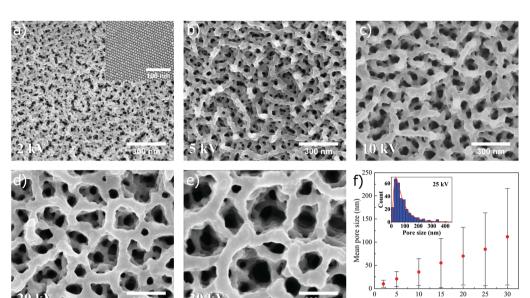


Fig. 3 Tuning the porosity of the resulting pore network during ion beam exposure of superstructures composed of nanospheres, by controlling the ion beam voltage at a constant dose of 0.5 nC μm^{-2} . (a-e) Show SEM micrographs of the resulting pore network after ion beam exposure at 2, 5, 10, 20 and 30 kV, respectively. (f) The measured pore sizes were fitted to a lognormal distribution, and mean values were found to increase in a linear manner with increasing ion beam voltage.

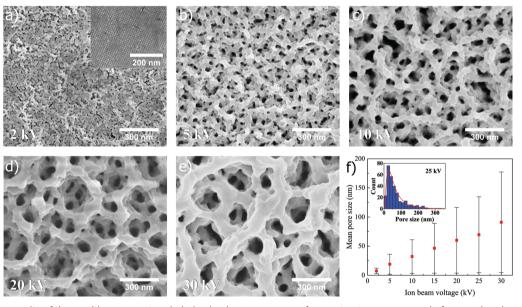


Fig. 4 Tuning the porosity of the resulting pore network during ion beam exposure of superstructures composed of nanocubes, by controlling the ion beam voltage at a constant dose of $0.5~\text{nC}~\mu\text{m}^{-2}$. (a-e) Show SEM micrographs of the resulting pore network after ion beam exposure at 2, 5, 10, 20 and 30 kV, respectively. (f) The measured pore sizes were fitted to a lognormal distribution, and mean values were found to increase in a linear manner with increasing ion beam voltage.

The Royal Society of Chemistry apologises for these errors and any consequent inconvenience to authors and readers.